









TESTCENTER

MICROSCOPY AND MICROSECTION ANALYSIS

We test comprehensively and reliably. With our wide range of equipment, we guarantee results.

| Macroscop | Technical data | Areas of application |
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|  | <ul style="list-style-type: none"> • Magnification up to 63x • Contrast technique: Lambda filter | <ul style="list-style-type: none"> • Documentation of optical coatings |
| Stereo microscop | Technical data | Areas of application |
|  | <ul style="list-style-type: none"> • Magnification up to 115x | <ul style="list-style-type: none"> • Microsection analysis • Solder joint analysis |

| Inverted light microscope | Technical data | Areas of application |
|--|--|---|
|  | <ul style="list-style-type: none"> • Magnification up to 1000x • Contrast technique: reflected light bright-field • Dark field • Polarization contrast • Differential interference contrast (DIC) | <ul style="list-style-type: none"> • Microsection analysis |
| Digital microscope | Technical data | Areas of application |
|  | <ul style="list-style-type: none"> • Magnification up to 400x • Creation of 3D images | <ul style="list-style-type: none"> • 3D images of surface structures |

| Optical microscope | Technical data | Areas of application |
|--|---|--|
|  | <ul style="list-style-type: none"> • Magnification up to 1000x • Contrast technique: polarization contrast | <ul style="list-style-type: none"> • Microsection analysis |
| REM with EDX | Technical data | Areas of application |
|  | <ul style="list-style-type: none"> • Magnification: 30 – 100,000x • Element determination, from boron to bismuth • SE and BSE analysis methods | <ul style="list-style-type: none"> • Surface images with high magnification • Surface structure and elemental distribution • Element analysis |